

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/708,424	CHEN ET AL.
	Examiner	Art Unit
	Jeffrey S. Zweizig	2816

SEARCHED			
Class	Subclass	Date	Examiner
327	308	2/9/2005	JZ
	309		
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
327	309	4/27/05	JZ
↓	541	↓	↓

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541 309